## SN54S133, SN74S133 13-INPUT POSITIVE-NAND GATES

DECEMBER 1983 - REVISED MARCH 1988

- Package Options Include Plastic "Small Outline" Packages, Ceramic Chip Carriers and Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instruments Quality and Reliability

#### description

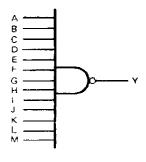
These devices contain a single 13-input NAND gate.

The SN54133 is characterized for operation over the full military temperature range of  $-55^{\circ}\text{C}$  to 125°C. The SN74133 is characterized for operation from 0°C to 70°C.

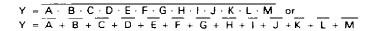
**FUNCTION TABLE** 

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#### logic diagram



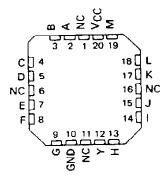
#### positive logic



SN54S133 . . . J OR W PACKAGE SN74S133 . . . D OR N PACKAGE (TOP VIEW)

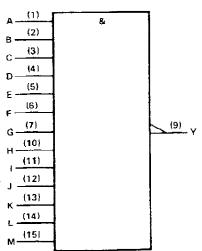
Α[	ī	U16 VCC
A [	2	15 🗍 M
c[	3	14 🔲 L
D[	4	13 🏻 K
E[	5	12 🔲 J
F	6	11[][
G[	7	10 🛮 H
GND [	8	9 \ Y

# SN54S133 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

## logic symbol†

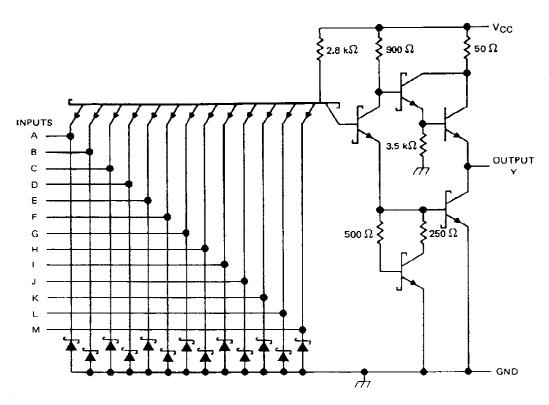


<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std 91 1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

#### schematic

'\$133



Resistor values shown are nominal.

## absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)		7 V
Input voltage	····	5.5 V
Operating free-air temperature range	SN54'	− 55° C to 125° C
	SN74'	0° C to 70° C
Storage temperature range	***************************************	65° C to 150° C

NOTE 1: Voltage values are with respect to network ground terminal.



## recommended operating conditions

<u>=</u>			SN54S133			SN74S133		
		MIN	NOM	МАХ	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.75	5	5.25	٧
ViH	High-level input voltage	2			2		""	٧
۷ŧL	Low-level input voltage			0.8			0.8	٧
ЮН	High-level output current			- 1			<b>– 1</b>	mA
IOL	Low-level output current			20			20	mA
TA	Operating free-air temperature	- 55		125	۵		70	°C

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS \$	SN54S133	SN74S133	UNIT
	TEST CONDITIONS ?	MIN TYP‡ MAX	MIN TYP‡ MAX	
VIK	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA	-1,2	-1.2	٧
V <sub>OH</sub>	V <sub>CC</sub> = MIN, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = -1 mA	2.5 3.4	2.7 3.4	٧
VOL	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, I <sub>OL</sub> = 20 mA	0.5	0.5	٧
11	V <sub>CC</sub> = MAX, V <sub>I</sub> = 5.5 V	1	1	mA
Iн	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V	50	50	μА
li L	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.5 V	-2	2	mΑ
los§	V <sub>CC</sub> - MAX	-40 -100	-40 -100	mΑ
іссн	V <sub>CC</sub> = MAX, V <sub>1</sub> = 0 V	3 5	3 5	mA
lccL	V <sub>CC</sub> = MAX, V <sub>I</sub> = 4.5 V	5.5 10	5.5 10	mΑ

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

## switching characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C (see note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONI	MIN TYP	MAX	UNIT	
tPLH			R <sub>ξ</sub> = 280 Ω,	C 15 of	4	6	ns
<sup>₹</sup> PHL	_		nt - 200 18,	Cլ = 15 pF	4.5	7	ns
¹PLH	Апу	Any Y	A <sub>L</sub> = 280 Ω, C <sub>L</sub> = 50 pF	0 50 5	5.5		пş
<sup>t</sup> PHL				CL = 90 pF	6.5		ns

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.

<sup>‡</sup> All typical values are at V<sub>CC</sub> = 5 V, TA = 25°C. § Not more than one output should be shorted at a time, and the duration of the short-circuit should not exceed one second.

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